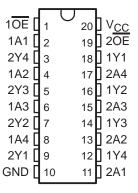
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- EPIC<sup>™</sup> (Enhanced-Performance Implanted CMOS) Submicron Process
- Output Ports Have Equivalent 26-Ω Series Resistors, So No External Resistors Are Required
- Typical V<sub>OLP</sub> (Output Ground Bounce)
   < 0.8 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot)
   2 V at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C
- Power Off Disables Outputs, Permitting Live Insertion
- Supports Mixed-Mode Signal Operation on All Ports (5-V Input/Output Voltage With 3.3-V V<sub>CC</sub>)
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages

### DB, DW, OR PW PACKAGE (TOP VIEW)



#### description

This octal buffer/line driver is designed for 1.65-V to 3.6-V  $V_{CC}$  operation.

The SN74LVC2244A is organized as two 4-bit line drivers with separate output-enable ( $\overline{OE}$ ) inputs. When  $\overline{OE}$  is low, the device passes data from the A inputs to the Y outputs. When  $\overline{OE}$  is high, the outputs are in the high-impedance state.

The outputs, which are designed to sink up to 12 mA, include equivalent 26- $\Omega$  resistors to reduce overshoot and undershoot.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

To ensure the high-impedance state during power up or power down,  $\overline{OE}$  should be tied to  $V_{CC}$  through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74LVC2244A is characterized for operation from -40°C to 85°C.

### FUNCTION TABLE (each buffer)

INP	JTS	OUTPUT
OE	Α	Υ
L H		Н
L	L	L
Н	Χ	Z



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

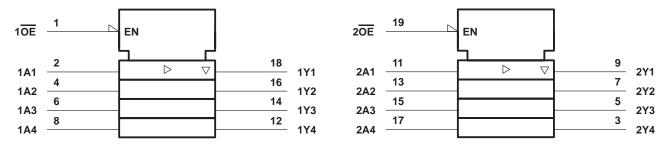
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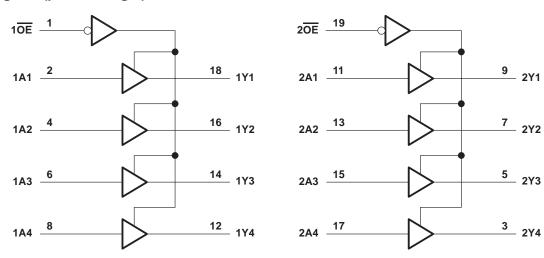
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#### logic symbol<sup>†</sup>



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

#### logic diagram (positive logic)



#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>	0.5 V to 6.5 V
Input voltage range, V <sub>I</sub> (see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high-impedance or power-off state, VO	
(see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high or low state, VO	
(see Notes 1 and 2)	–0.5 V to V <sub>CC</sub> + 0.5 V
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	–50 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	–50 mA
Continuous output current, I <sub>O</sub>	±50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 3): DB package	115°C/W
DW package	97°C/W
PW package	128°C/W
Storage temperature range, T <sub>Stq</sub>	–65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.
  - 2. The value of V<sub>CC</sub> is provided in the recommended operating conditions table.
  - 3. The package thermal impedance is calculated in accordance with JESD 51.



#### recommended operating conditions (see Note 4)

			MIN	MAX	UNIT				
Vсс	Supply voltage	Operating	1.65	3.6	V				
	Supply voltage	Data retention only	1.5		V				
	High-level input voltage	$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	0.65 × V <sub>CC</sub>						
VIH		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V				
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2						
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$		0.35 × V <sub>CC</sub>					
VIL	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		0.7	T v				
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8					
٧ı	Input voltage	<u>-</u>	0	5.5	V				
\/ -	Output voltage	High or low state	0	Vcc	V				
۷o		3 state	0	5.5					
	High-level output current	V <sub>CC</sub> = 1.65 V		-2					
l ,		V <sub>CC</sub> = 2.3 V		-4	A				
ЮН		$V_{CC} = 2.7 \text{ V}$		-8	mA				
		V <sub>CC</sub> = 3 V		-12					
	Low-level output current	V <sub>CC</sub> = 1.65 V		2					
lOL		$V_{CC} = 2.3 \text{ V}$		4	mA				
		V <sub>CC</sub> = 2.7 V		8	IIIA				
		V <sub>CC</sub> = 3 V		12					
Δt/Δν	Input transition rise or fall rate	-	0	10	ns/V				
TA	Operating free-air temperature		-40	85	°C				

NOTE 4: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



#### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST C	CONDITIONS	VCC	MIN	TYP <sup>†</sup>	MAX	UNIT	
	I <sub>OH</sub> = -100 μA	1.65 V to 3.6 V	V <sub>CC</sub> -0.	.2				
	I <sub>OH</sub> = -2 mA	1.65 V	1.2					
	1 2 4 20 4	2.3 V	1.7			V		
Voн	I <sub>OH</sub> = -4 mA	2.7 V	2.2					
	I <sub>OH</sub> = -6 mA	3 V	2.4					
	I <sub>OH</sub> = -8 mA		2.7 V	2				
	I <sub>OH</sub> = -12 mA		3 V	2				
	I <sub>OL</sub> = 100 μA		1.65 V to 3.6 V			0.2		
	I <sub>OL</sub> = 2 mA	1.65 V			0.45			
	1 m   1	4 mA				0.7	V	
V <sub>OL</sub>	I <sub>OL</sub> = 4 mA	2.7 V			0.4			
	I <sub>OL</sub> = 6 mA	3 V			0.55			
	I <sub>OL</sub> = 8 mA	2.7 V			0.6			
	I <sub>OL</sub> = 12 mA	3 V			0.8			
lį	V <sub>I</sub> = 0 to 5.5 V		3.6 V			±5	μΑ	
l <sub>off</sub>	V <sub>I</sub> or V <sub>O</sub> = 5.5 V		0			±10	μΑ	
loz	V <sub>O</sub> = 0 to 5.5 V		3.6 V			±10	μΑ	
1	V <sub>I</sub> = V <sub>CC</sub> or GND	1- 0	2.6.1/			10	A	
lcc	$3.6 \text{ V} \le \text{V}_{\text{I}} \le 5.5 \text{ V}^{\ddagger}$	IO = 0	3.6 V			10	μΑ	
ΔlCC	One input at V <sub>CC</sub> – 0.6 V,	Other inputs at V <sub>CC</sub> or GND	2.7 V to 3.6 V			500	μΑ	
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND		3.3 V		4		pF	
Co	$V_O = V_{CC}$ or GND		3.3 V		5.5		pF	

<sup>†</sup> All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. ‡ This applies in the disabled state only.

# switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = ± 0.1		V <sub>CC</sub> =	2.5 V 2 V	V <sub>CC</sub> =	2.7 V	V <sub>CC</sub> =	3.3 V 3 V	UNIT	
	(INPOT)	(001F01)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
t <sub>pd</sub>	А	Υ	§	§	§	§		6.4	1.5	5.5	ns	
t <sub>en</sub>	ŌĒ	Y	§	§	§	§		8.1	1	7.1	ns	
t <sub>dis</sub>	ŌĒ	Υ	§	§	§	§		7.3	1.5	6.8	ns	

<sup>§</sup> This information was not available at the time of publication.

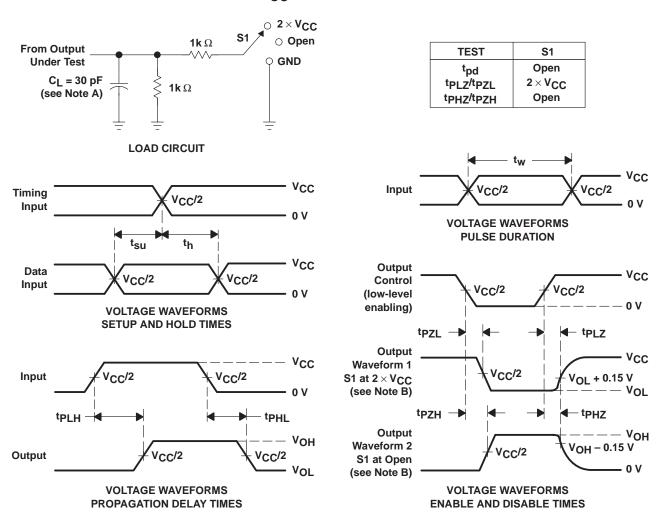
### operating characteristics, T<sub>A</sub> = 25°C

ſ		PARAMETER		TEST CONDITIONS	V <sub>CC</sub> = 1.8 V ± 0.15 V	V <sub>CC</sub> = 2.5 V ± 0.2 V	V <sub>CC</sub> = 3.3 V ± 0.3 V	UNIT	
L				CONDITIONS	TYP	TYP	TYP		
Γ	Card	Power dissipation capacitance	Outputs enabled	f = 10 MHz	§	§	46	pF	
C <sub>pd</sub>	per buffer/driver	Outputs disabled	T = 10 WIHZ	§	§	2	PΓ		

<sup>§</sup> This information was not available at the time of publication.



## PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$

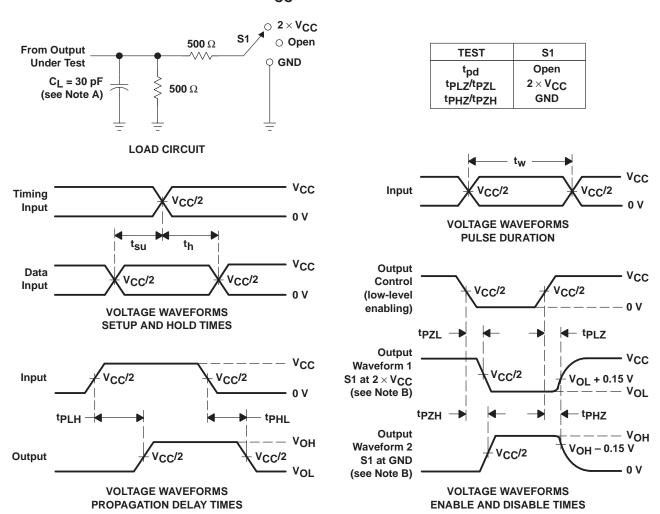


NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq 2$  ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

### PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$



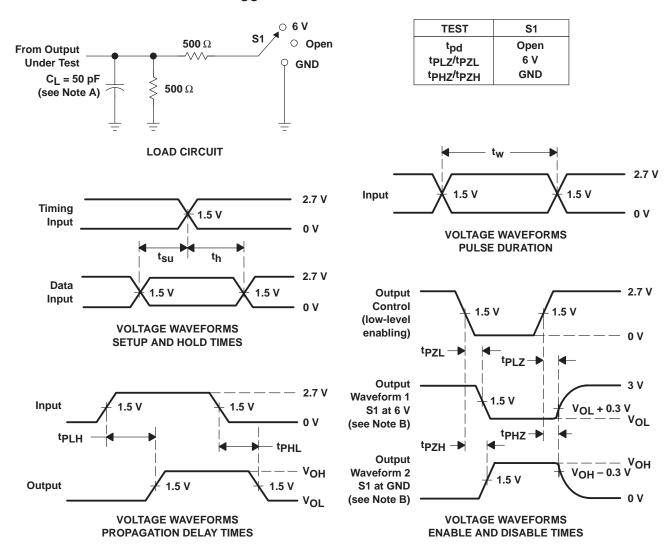
NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq 2$  ns.  $t_f \leq 2$  ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



## PARAMETER MEASUREMENT INFORMATION $V_{CC}$ = 2.7 V AND 3.3 V $\pm$ 0.3 V



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_Q = 50 \,\Omega$ ,  $t_f \leq 2.5 \,\text{ns}$ ,  $t_f \leq 2.5 \,\text{ns}$ .
- D. The outputs are measured one at a time with one transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms

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